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TECHNICAL REPORT



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TECHNICAL REPORT

Dynamic modulesiTeh STANDARD PREVIEW Part 6-6: Design guide – Failure mode effect analysis for optical units of dynamic modules

> <u>IEC TR 62343-6-6:2017</u> https://standards.iteh.ai/catalog/standards/sist/1e287528-ed37-42e9-a302c5b0a2887fc2/iec-tr-62343-6-6-2017

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

DYNAMIC MODULES –

Part 6-6: Design guide – Failure mode effect analysis for optical units of dynamic modules

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IEC 62343-6-6, which is a Technical Report, has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

This second edition cancels and replaces the first edition published in 2011. It constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

a) addition of the LCOS based and the DLP based wavelength selective switch (WSS);

b) addition of the multicast optical switch module (MCOS).

The text of this technical report is based on the following documents:

DTR	Report on voting
86C/1396/DTR	86C/1421/RVC

Full information on the voting for the approval of this technical report can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62343 series, published under the general title *Dynamic modules*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended. **iTeh STANDARD PREVIEW**

A bilingual version of this publication may be issued at a later date.

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DYNAMIC MODULES -

Part 6-6: Design guide – Failure mode effect analysis for optical units of dynamic modules

1 Scope

This part of IEC 62343, which is a Technical Report, describes failure mode effect analysis (FMEA) for optical units of dynamic modules. FMEA is one of the effective and useful analysis methods to determine the reliability evaluation test items and conditions that are defined in future reliability qualification documents.

In order to estimate the lifetime for a module, there is a typical procedure. The first step is to identify the dominant failure modes. The second step is to determine the acceleration tests according to these failure modes. The third step is to carry out the test. The fourth step is to estimate the acceleration factors. Finally, the fifth step is to calculate the lifetime of the dynamic module.

IEC 61300-2 (all parts) defines environment and mechanical tests. This Technical Report describes the dominant failure mode for dynamic modules and relevant tests from IEC 61300-2 (all parts). Ten STANDARD PREVIEW

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2 Normative references

IEC TR 62343-6-6:2017

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61300-2-1, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-1: Tests – Vibration (sinusoidal)

IEC 61300-2-4, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-4: Tests – Fibre/cable retention

IEC 61300-2-9, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-9: Tests – Shock

IEC 61300-2-17, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-17: Tests – Cold

IEC 61300-2-18, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-18: Tests – Dry heat – High temperature endurance

IEC 61300-2-19, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-19: Tests – Damp heat (steady state)

IEC 61300-2-22, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-22: Tests – Change of temperature

IEC 61300-2-44, Fibre optic interconnecting devices and passive components – Basic test and measurement procedures – Part 2-44: Tests – Flexing of the strain relief of fibre optic devices

3 Terms and definitions

No terms and definitions are listed in this document.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at http://www.electropedia.org/
- ISO Online browsing platform: available at http://www.iso.org/obp

4 Consideration of types of dynamic modules

There are many types of dynamic modules: dynamic channel equalizer, tuneable optical chromatic dispersion compensator, dynamic gain tilt equalizer, wavelength selective switch, wavelength blocker, optical performance monitor, optical switch, and so on. The main feature of dynamic modules is to control their performances during operation. In order to achieve their features, many kinds of control mechanisms are used for dynamic modules; micro electro mechanical system (MEMS), stepping motor, electromagnet, thermo optics, magnet optics, electro optics, liquid crystal device (LCD), and so on. PREVIEW

Table 1 shows the first guidance of categorization of dynamic modules and their mode of evaluation. Dynamic modules without an electrical circuit board can be considered similar to passive optical components for purposes of evaluation. On the other hand, for dynamic modules with a control circuit board, it is necessary to give special consideration. There are mainly two types of internal design for dynamic modules: those for which it is not easy to divide the constituting parts to consider the reliability, and those for which it is not easy to divide. It is necessary to consider how to evaluate according to these structures.

This document describes FMEA only for optical units for dynamic modules. It is necessary to evaluate whole dynamic modules including control circuit boards and firmware if used.

5 Typical failure points

In addition to control circuit boards and control of moving parts, a typical optical unit for a dynamic module consists of the following parts: optical element, outer package, fibre pigtails, optical semiconductor chips, and joint points of these elements. These elements have their own failure mode; for example, break for pigtails and displacement for joint points. Moreover, these elements may have their acceleration factor of degradation; for example, joint points fixed by adhesive are generally weak against high humidity. This failure mode analysis can be referred to FMEA for passive optical components (refer to IEC 62005-3).

There are special considerations for dynamic modules. The following are some examples:

- when using MEMS, operating shock and vibration test are necessary because MEMS are sensitive to mechanical shock and vibration;
- when temperature control is used, the temperature cycling test is recommended because temperature control functions generally produce thermal stress;
- The temperature cycling test can accelerate thermal stress.

6 Failure modes and known failure mechanisms

For some dynamic modules, FMEA is carried out. Table 2 shows known failure mechanisms, failure effects, failure modes, relevant tests, and IEC test document numbers for dynamic modules. If new technology and new dynamic modules become commercially available, they will be added to Table 2 in later revisions of this document. Relevant tests are listed with the failure effect and the dominant failure mechanism. As other relevant tests or methods of failure mode excitation become known, these will also be added.

Table 1 – Categorization based on the structure and mode of evaluation

Ele	ectrical circuits	How to evaluate	Examples
Without electrical circuits	N.A.	As optical component	VOA, 1x2/2x2 optical switch, DGTE
With electrical circuit	Easy to divide optical and electrical unit	As optical and electrical units individually, and as integrated dynamic module	VOA, VOA-MUX, TDC (DCDC), DCE, matrix switch, channel monitor, performance monitor
	Difficult to divide optical and electrical unit	To evaluate as integrated dynamic module	Wavelength blocker (WB), Wavelength selective switch (WSS)

IEC 62572 (all parts) for active components should comply with the reliability qualification requirement defined in IEC 62572 (all parts) for active components and IEC 62005-9 (all parts) for passive optical components, respectively. In cases in which it is difficult to divide optical and electrical units, integrated modules should be tested.

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Electrical circuit boards should be qualified individually. The following standards series are useful references for the quality of electrical circuit boards: **JEC 61188 (all parts), IEC 61189** (all parts), IEC 61190 (all parts), and IEC 61191 (all parts).

Three pieces should be tested.

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https://standards.iteh.ai/catalog/standards/sist/1e287528-ed37-42e9-a302c5b0a2887fc2/iec-tr-62343-6-6-2017 Table 2 – Failure mode and known failure mechanisms for the optical units of dynamic devices

Dynamic devices	Constitution parts	ution ts	Known failure mechanisms	Failure modes	Degradation acceleration factors	Relevant tests	IEC references
Variable optical MEMS type attenuators	type MEMS.h	I SI S	standards.iteh.ai	WeotrallabeW	Mechanical stress Excess driving power	Shock (storage) Vibration (storage) Maximum absolute rating test (electrical)	
		-	IEC TR 62343-6-6:2017			On/off driving test	Under study
	https://standards.itel		Disconsion standards/snirrole ²⁸ b0a2887fc2/iec-tr-62343-6-6	1785 etfon 1058 increase 2017 Attenuation change	Mechanical stress Thermal stress	Shock (storage) Vibration (storage)	IEC 61300-2-9 IEC 61300-2-1
				Return loss decrease Dvnamic range of	Excess driving power	Shock and vibration (operating)	Under study IFC 61300-2-22
				attenuation decrease		Change of temperature	Under study
				WDL increase		Dn/off driving test	Under study
		-	Reflectance of mirror changing	Insertion loss increase Attenuation change	High humidity (non-hermetic sealed)	Damp heat	IEC 61300-2-19
				Return loss decrease			
				PDL increase WDL increase			
	Collimator		Dislocation of fixing points of optical parts	Insertion loss increase Attenuation change	Thermal stress	Change of temperature	IEC 61300-2-22
				Dynamic range of attenuation decrease	right number (non-nermence) sealed and using adhesive) Mechanical stress	Damp heat	IEC 61300-2-19
				PDL increase WDL increase		Shock (storage) Vibration (storage)	IEC 61300-2-9 IEC 61300-2-1
	Pigtail		Fibre broken, micro-	Insertion loss increase	Mechanical stress for pigtail	Fibre cable retention	IEC 61300-2-4
			6 up tead	No operation		Optical fibre cable flexing	IEC 61300-2-44

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Liquid crystal type LCD Degradation of LCD Insertion loss i Attenuation ch. iTTeh STANDARD P Return visege Attenuation ch. iTTeh STANDARD P Petun visege Attenuation de Standards.itch Petun visege Attenuation de PDL increase non-return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return return r	Dynamic devices	sec	Constitution parts	Known failure mechanisms	Failure modes	Degradation acceleration factors	Relevant tests	IEC references
iTch STANDARD PI (standards.iteh (standards.iteh)	Liqu	bit bit	LCD		Insertion loss increase	Thermal stress	Change of temperature	IEC 61300-2-22
iTch STANDARD PI (standards.itel arited standards.itel BCTR 62343-6-62017 ECTR 62343-6-62017 ECTR 62343-6-62017 ECTR 62343-6-62017 Freezing of LCD Collimator Same as MEMS type Magnet optic Same as MEMS type Magnet optic Dislocation of magnet, part Pigtail Same as MEMS type Collimator Same as MEMS type Pigtail Same as MEMS type Pigtail Same as MEMS type Pigtail Same as MEMS type Moving part Stacking the moving part	crys	stal type			Attenuation change	High humidity (non-hermetic	High temperature	IEC 61300-2-18
Ss//standards.itel IEC TR 62343-6-62017 Collimator Same as MEMS type Pigtail Same as MEMS type Pigtail Same as MEMS type Pigtail Same as MEMS type Pointefringent crystal binefringent crystal Noving part Stacking the moving part			iTeh Sl	PI (Return loss decrease	sealed)	Damp heat	IEC 61300-2-19
Ss//standards.itel IEC TR 62343-6-62017 Ss//standards.itel accarate of an electron of a control of the standard state of LCD Collimator Same as MEMS type Pigtail Same as MEMS type Magnet optic Dislocation of magnet, part part Ereaday rotator and birefringent crystal Moving part Same as MEMS type Magnet optic Dislocation of magnet, part part Birefringent crystal Moving part Stacking the moving part			S	teh	Dynamic range of	Mechanical stress	Shock (storage)	IEC 61300-2-9
IEC TR 62343-6-62017 Ss://standards.ticlet.ericent.log/stm.dir.ut/s.siv11628 Collimator Ereezing of LCD Collimator Same as MEMS type Pigtail Same as MEMS type Magnet optic Dislocation of magnet, part Part Same as MEMS type Pigtail Same as MEMS type Part Same as MEMS type Prigtail Same as MEMS type Moving part Stacking the moving part					PDL increase		Vibration (storage)	IEC 61300-2-1
Collimator Same as MEMS type Freezing of LCD Collimator Same as MEMS type Pigtail Same as MEMS type Magnet optic Dislocation of magnet, part Franday rotator and birefringent crystal birefringent crystal Collimator Same as MEMS type Pigtail Same as MEMS type Moving part Stacking the moving part		444	aci//atondonda itali		WDL increase			
Freezing of LCD Freezing of LCD Collimator Same as MEMS type Pigtail Same as MEMS type Magnet optic Dislocation of magnet, part Part Dislocation of magnet, part birefringent crystal birefringent crystal Pigtail Same as MEMS type Part Birefringent crystal birefringent crystal birefringent crystal Moving part Stacking the moving part				Flectrical polarization of 6-6.	Uncontrollable	Excess driving power	Maximum absolute rating	Under study
Freezing of LCD Collimator Same as MEMS type Pigtail Same as MEMS type Magnet optic Dislocation of magnet, Faraday rotator and birefringent crystal Dollimator Same as MEMS type Pigtail Same as MEMS type Pigtail Same as MEMS type Moving part Stacking the moving part				LCU			test On/off driving test	Under study
CollimatorSame as MEMS typePigtailSame as MEMS typeMagnet opticDislocation of magnet, partMagnet opticDislocation of magnet, birefringent crystalDartDislocation of magnet, birefringent crystalDartSame as MEMS typeCollimatorSame as MEMS typePigtailSame as MEMS typeMoving partStacking the moving part					Uncontrollable	Low temperature	Cold	IEC 61300-2-17
PigtailSame as MEMS typeMagnet opticDislocation of magnet, Faraday rotator and birefringent crystalDistringent crystalSame as MEMS typeCollimatorSame as MEMS typePigtailSame as MEMS typeMoving partStacking the moving part			Collimator	Same as MEMS type				
Magnet optic Dislocation of magnet, part Earaday rotator and birefringent crystal Collimator Same as MEMS type Pigtail Same as MEMS type Moving part Stacking the moving part			Pigtail	Same as MEMS type				
part Faraday rotator and birefringent crystal Collimator Same as MEMS type Pigtail Same as MEMS type Moving part Stacking the moving part	Mag	jnet optic	Magnet optic		Insertion loss increase	Thermal stress	Change of temperature	IEC 61300-2-22
Collimator Same as MEMS type Pigtail Same as MEMS type anical Moving part	type	0	part	Faraday rotator and birefringent crystal	Attenuation change	High humidity (non-hermetic	High temperature	IEC 61300-2-18
Collimator Same as MEMS type Pigtail Same as MEMS type nanical Moving part					Return loss decrease	sealed and using adnesive)	Damp heat	IEC 61300-2-19
Collimator Same as MEMS type Collimator Same as MEMS type Pigtail Same as MEMS type nanical Moving part					Dynamic range of	Mechanical stress	Shock (storage)	IEC 61300-2-9
Collimator Same as MEMS type Pigtail Same as MEMS type nanical Moving part					attenuation decrease		Vibration (storage)	IEC 61300-2-1
Collimator Same as MEMS type Pigtail Same as MEMS type nanical Moving part					PDL increase)	
Collimator Same as MEMS type Pigtail Same as MEMS type nanical Moving part					WDL increase			
Pigtail Same as MEMS type nanical Moving part			Collimator	Same as MEMS type				
nanical Moving part Stacking the moving part			Pigtail	Same as MEMS type				
addi	Mec	chanical	Moving part	part	Uncontrollable	Mechanical stress	Shock (storage)	IEC 61300-2-9
	INDE					High humidity (non-hermetic)	Vibration (storage)	IEC 61300-2-1
						Excess driving power	Damp heat	IEC 61300-2-19
							Maximum absolute rating test (electrical)	_
							On/off driving test	Under study

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Dynamic devices	Constitution parts	Known failure mechanisms	Failure modes	Degradation acceleration factors	Relevant tests	IEC references
		Degradation of moving part	Driving power increase	Mechanical stress	Shock (storage)	IEC 61300-2-9
				Thermal stress	Vibration (storage)	IEC 61300-2-1
	iTeh S	iTeh STANDARD PI	PREVIEW	Excess driving power	Shock and vibration	Under study
		(standards iteh ai)	ai)	High humidity (non-hermetic	(operating) Change of temperature	IEC 61300-2-22
				seared)		Under study
		IEC TR 62343-6-6:2017			Maximum absolute rating test	Under study
lh	tps://standards.ite	https://standards.itel.ai/catalog/standards/sist/1e287528-ed37-42e9-a302- o4boo3807#07/soc # 60243 6 / 2017	'528-ed37-42e9-a302- 2017		On/off driving test	IEC 61300-2-19
	ذ	1004200/102/102-11-02242-0-0.	/ 107.		Damp heat	
		Distortion of mirror	Insertion loss increase	Mechanical stress	Shock (storage)	IEC 61300-2-9
			Return loss decrease	Thermal stress	Vibration (storage)	IEC 61300-2-1
			Crosstalk increase	Excess driving power	Change of temperature	IEC 61300-2-22
			PDL increase		Maximum absolute rating	Under study
					test On/off driving test	Under study
		Reflectance of mirror	Insertion loss increase	High humidity (non-hermetic	Damp heat	IEC 61300-2-19
		Sub man	Attenuation change			
			Return loss decrease			
			PDL increase			
			WDL increase			
	Collimator	Same as MEMS type				
	Pigtail	Same as MEMS type				
Planar	Waveguide	Refractive index changing	Insertion loss increase	Thermal stress	Change of temperature	IEC 61300-2-22
type (thermal				High humidity (non-hermetic	High temperature	IEC 61300-2-18
optic effect)			Keturn loss decrease	sealed and using adhesive)	Damp heat	IEC 61300-2-19
			Dynamic range of attenuation decrease	Mechanical stress	Shock (storage)	IEC 61300-2-9
			PDL increase		Vibration (storage)	IEC 61300-2-1